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# TABLE OF CONTENTS

<b>Modeling and Mitigating NBTI in Nanoscale Circuits</b> .....	1
<i>S. Khan, S. Hamdioui</i>	
<b>Investigation of Multi Cell Upset in Sequential Logic and Validity of Redundancy Technique</b> .....	7
<i>T. Uemura, T. Kato, H. Matsuyama, K. Takahisa, M. Fukuda, K. Hatanaka</i>	
<b>High-Level Synthesis for Multi-Cycle Transient Fault Tolerant Datapaths</b> .....	13
<i>T. Inoue, H. Henmi, Y. Yoshikawa, H. Ichihara</i>	
<b>An Intellectual Property Core to Detect Task Scheduling-Related Faults in RTOS-Based Embedded Systems</b> .....	19
<i>D. Silva, L. Bolzani, F. Vargas</i>	
<b>RVC-Based Time-Predictable Faulty Caches for Safety-Critical Systems</b> .....	25
<i>J. Abella, E. Quinones, F. Cazorla, M. Valero, Y. Sazeides</i>	
<b>Towards Functional-Safe Timing-Dependable Real-Time Architectures</b> .....	31
<i>M. Paolieri, R. Mariani</i>	
<b>Matrix Control-Flow Algorithm-Based Fault Tolerance</b> .....	37
<i>R. Ferreira, A. Moreira, L. Carro</i>	
<b>Selective Fault Tolerance for Finite State Machines</b> .....	43
<i>M. Augustin, M. Gossel, R. Kraemer</i>	
<b>A New IP Core For Fast Error Detection And Fault Tolerance In COTS-Based Solid State Mass Memories</b> .....	49
<i>E. Costenaro, M. Violante, D. Alexandrescu</i>	
<b>Variability-Aware Task Mapping Strategies For Many-Cores Processor Chips</b> .....	55
<i>F. Chaix, G. Bizot, M. Nicolaidis, N. Zergainoh</i>	
<b>On Graceful Degradation of Microprocessors in Presence of Faults via Resource Banking</b> .....	61
<i>R. Rodrigues, S. Kundu</i>	
<b>On Graceful Degradation of Chip Multiprocessors in Presence of Faults via Flexible Pooling of Critical Execution Units</b> .....	67
<i>R. Rodrigues, S. Kundu</i>	
<b>A Multi-Objective Optimization For Memory BIST Sharing Using A Genetic Algorithm</b> .....	73
<i>L. Zaourar, Y. Kieffer, A. Wenzel</i>	
<b>Memory BIST with Address Programmability</b> .....	79
<i>A. Fradi, M. Nicolaidis, L. Anghel</i>	
<b>Generic BIST Architecture for Testing of Content Addressable Memories</b> .....	86
<i>H. Grigoryan, G. Harutyunyan, S. Shoukourian, V. Vardanian, Y. Zorian</i>	
<b>A Reliable Fault Classifier for Dependable Systems on SRAM-based FPGAs</b> .....	92
<i>C. Bolchini, C. Sandionigi, L. Fossati, D. Codinachs</i>	
<b>An Approach To Reduce Computational Cost In Combinatorial Logic Netlist Reliability Analysis Using Circuit Clustering And Conditional Probabilities</b> .....	98
<i>J. Flaquer, J. Daveau, L. Naviner, P. Roche</i>	
<b>Estimation of Component Criticality in Early Design Steps</b> .....	104
<i>M. Sauer, A. Czutro, I. Polian, B. Becker</i>	
<b>New Reliability Mechanisms in Memory Design for sub-22nm Technologies</b> .....	111
<i>N. Aymerich, A. Asenov, A. Brown, R. Canal, B. Cheng, J. Figueras, A. Gonzalez, E. Herrero, S. Markov, M. Miranda, P. Pouyan, T. Ramirez, A. Rubio, I. Vatajelu, X. Vera, P. Zuber</i>	
<b>A BIST Scheme for Testing and Repair of Multi-Mode Power Switches</b> .....	115
<i>Z. Zhang, X. Kavousianos, Y. Tsiatouhas, K. Chakrabarty</i>	
<b>Internal Model Control for a Self-Tuning Delay-Locked Loop in UWB Communication Systems</b> .....	121
<i>R. Alhakim, E. Simeu, K. Raouf</i>	
<b>Real Time Cross-Layer Adaptation for Minimum Energy Wireless Image Transport Using Bit Error Rate Control</b> .....	127
<i>J. Natarajan, S. Sen, A. Chatterjee</i>	
<b>The Cost of Cryptography: Is Low Budget Possible?</b> .....	133
<i>I. Verbauwhede</i>	
<b>Countermeasures against Fault Attacks: the Good, the Bad, and the Ugly</b> .....	134
<i>P. Maistri</i>	
<b>Rise of the Hardware Trojans</b> .....	138
<i>B. Sunar</i>	

<b>A Novel Radiation Tolerant SRAM Design Based on Synergetic Functional Component Separation for Nanoscale CMOS .....</b>	<b>139</b>
<i>Y. Shiyankovskii, A. Rajendran, C. Papachristou</i>	
<b>Noise Margin, Critical Charge and Power-Delay Tradeoffs for SRAM Design .....</b>	<b>145</b>
<i>A. Rajendran, Y. Shiyankovskii, F. Wolff, C. Papachristou</i>	
<b>Multiple-Bit-Upset and Single-Bit-Upset Resilient 8T SRAM Bitcell Layout with Divided Wordline Structure.....</b>	<b>151</b>
<i>S. Yoshimoto, T. Amashita, D. Kozuwa, T. Takata, M. Yoshimura, Y. Matsunaga, H. Yasuura, H. Kawaguchi, M. Yoshimoto</i>	
<b>Error Correction Encoding for Multi-threshold Capture Mechanism .....</b>	<b>157</b>
<i>K. Karmarkar, S. Tragoudas</i>	
<b>Reduced Overhead Soft Error Mitigation Using Error Control Coding Techniques .....</b>	<b>163</b>
<i>V. Prasanth, V. Singh, R. Parekhji</i>	
<b>Soft Error Correction in Embedded Storage Elements.....</b>	<b>169</b>
<i>M. Imhof, H. Wunderlich</i>	
<b>A Comprehensive Soft Error Analysis Methodology for SoCs/ASICs Memory Instances.....</b>	<b>175</b>
<i>D. Alexandrescu</i>	
<b>A Verification Strategy for Fault-Detection and Fault-Tolerance Circuits .....</b>	<b>177</b>
<i>G. Boschi, R. Mariani, S. Lorenzini</i>	
<b>Accelerating Secure Circuit Design with Hardware Implementation of Diehard Battery of Tests of Randomness .....</b>	<b>179</b>
<i>A. Vaskova, C. Lopez-Ongil, E. Millan, A. Jimenez-Horas, L. Entrena</i>	
<b>An FPGA-Based Framework for Run-time Injection and Analysis of Soft Errors in Microprocessors .....</b>	<b>182</b>
<i>M. Sauer, V. Tomashevich, J. Muller, M. Lewis, A. Spilla, I. Polian, B. Becker, W. Burgard</i>	
<b>An On-Line Memory State Validation using Shadow Memory Cloning.....</b>	<b>186</b>
<i>M. Baklashov</i>	
<b>Control-flow Error Recovery Using Commodity Multi-core Architecture Features.....</b>	<b>190</b>
<i>N. Khoshavi, H. Zarandi, M. Maghsoudloo</i>	
<b>Detection Of Trojan HW By Using Hidden Information On The System .....</b>	<b>192</b>
<i>O. Keren, I. Levin, V. Sinelnikov</i>	
<b>Fault Attack Resistant Deterministic Random Bit Generator usable for Key Randomization.....</b>	<b>194</b>
<i>E. Bohl, P. Duplys</i>	
<b>Fault-Tolerance Assessment and Enhancement in SoCWire Interface: A System-On-Chip Wire.....</b>	<b>196</b>
<i>R. Salamat, H. Zarandi</i>	
<b>Generalized Parity-Check Matrices for SEC-DED Codes with Fixed Parity .....</b>	<b>198</b>
<i>V. Gherman, S. Evain, N. Seymour, Y. Bonhomme</i>	
<b>ICT: Interface Software for the Characterization and Test of Mixed-Signal Power Cores .....</b>	<b>202</b>
<i>J. Esteves, T. Moita, C. Almeida, M. Santos</i>	
<b>Loopback Output Router For Reliable Network On Chip.....</b>	<b>206</b>
<i>C. Killian, C. Tanougast, F. Monteiro, A. Dandache</i>	
<b>Multi-Level Secure JTAG Architecture.....</b>	<b>208</b>
<i>L. Pierce, S. Tragoudas</i>	
<b>Self-Checking Test Circuits for Latches and Flip-Flops.....</b>	<b>210</b>
<i>R. Ribas, Y. Sun, A. Reis, A. Ivanov</i>	
<b>Software-based Control Flow Error Detection and Correction Using Branch Triplication .....</b>	<b>214</b>
<i>N. Ghalaty, M. Fazeli, H. Rad, S. Miremadi</i>	
<b>Variations of Fault Manifestation during Burn-In - A Case Study on Industrial SRAM Test Results -.....</b>	<b>218</b>
<i>M. Linder, A. Eder, K. Oberlander, M. Huch</i>	
<b>A Side Channel Attack Countermeasure using System-On-Chip Power Profile Scrambling .....</b>	<b>222</b>
<i>A. Krieg, J. Grinschgl, C. Steger, R. Weiss, J. Haid</i>	
<b>AKARI-X: A Pseudorandom Number Generator For Secure Lightweight Systems .....</b>	<b>228</b>
<i>H. Martin, E. Millan, L. Entrena, P. Lopez</i>	
<b>Algebraic Manipulation Detection Codes and Their Applications for Design of Secure Cryptographic Devices .....</b>	<b>234</b>
<i>Z. Wang, M. Karpovsky</i>	
<b>Towards Improved Survivability in Safety-Critical Systems.....</b>	<b>240</b>
<i>J. Abella, F. Cazorla, E. Quinones, D. Gizopoulos, A. Grasset, S. Yehia, P. Bonnot, R. Mariani, G. Bernat</i>	
<b>A Robust Algorithm for Pessimistic Analysis of Logic Masking Effects in Combinational Circuits.....</b>	<b>246</b>
<i>T. Takata, Y. Matsunaga</i>	
<b>An Analytical Model for the Calculation of the Expected Miss Ratio in Faulty Caches .....</b>	<b>252</b>
<i>D. Sanchez, Y. Sazeides, J. Aragon, J. Garcia</i>	

<b>Evaluation Techniques for On-line Testing of Robust Systems Based on Critical Tasks Distribution .....</b>	<b>258</b>
<i>A. Vaskova, C. Lopez-Ongil, M. Garcia-Valderas, M. Portela-Garcia, L. Entrena</i>	
<b>Unidirectional Error Detection, Localization and Correction for DRAMs: Application to On-Line</b>	
<b>DRAM Repair Strategies .....</b>	<b>264</b>
<i>N. Madalin, L. Miclea, J. Figueras</i>	
<b>An Effective Methodology for On-line Testing of Embedded Microprocessors .....</b>	<b>270</b>
<i>P. Bernardi, L. Ciganda, E. Sanchez, M. Reorda</i>	
<b>Fail-Safety in Core-Based System Design .....</b>	<b>276</b>
<i>R. Baranowski, H. Wunderlich</i>	
<b>Author Index</b>	